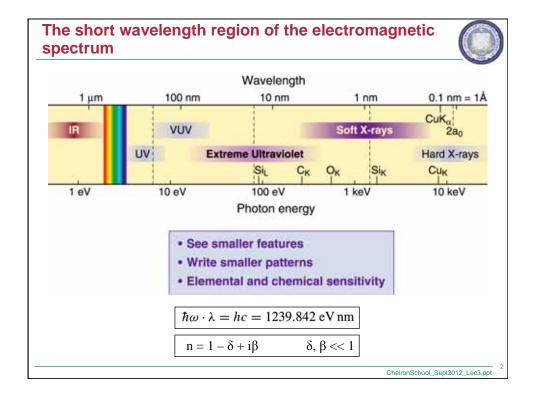


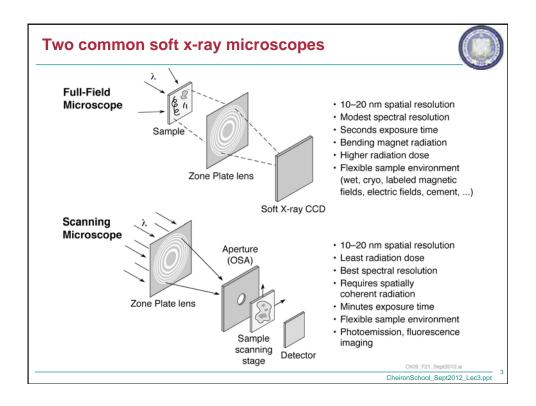
## Soft and Hard X-Ray Microscopy

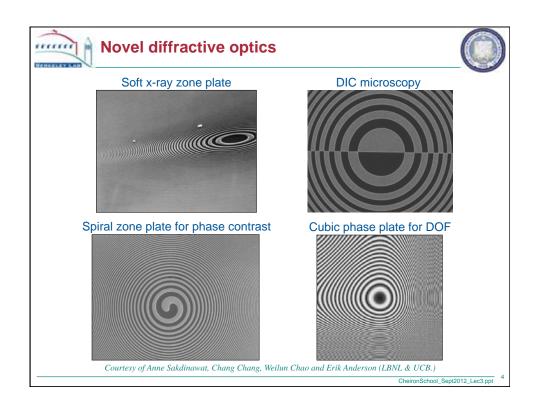
## David Attwood University of California, Berkeley

Cheiron School September 2012 SPring-8

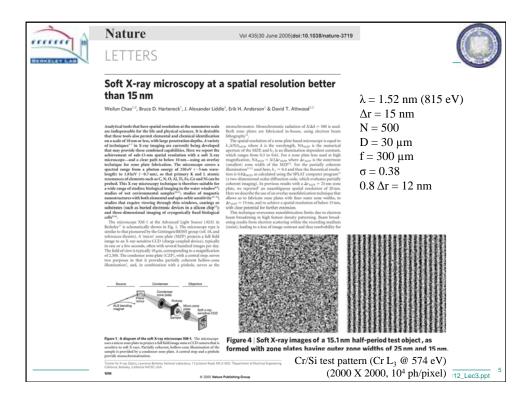
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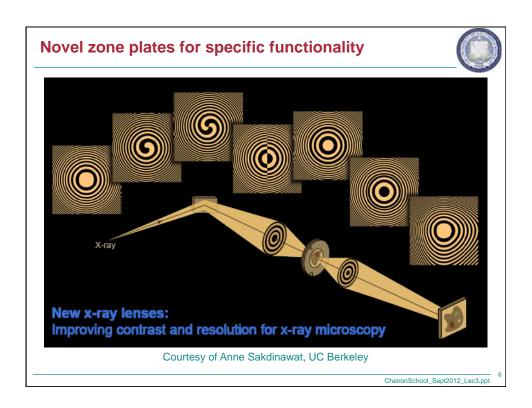


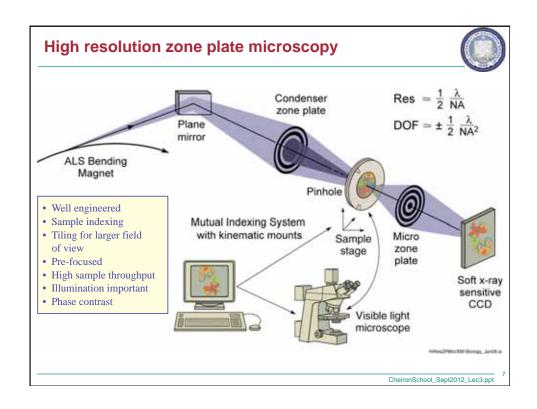


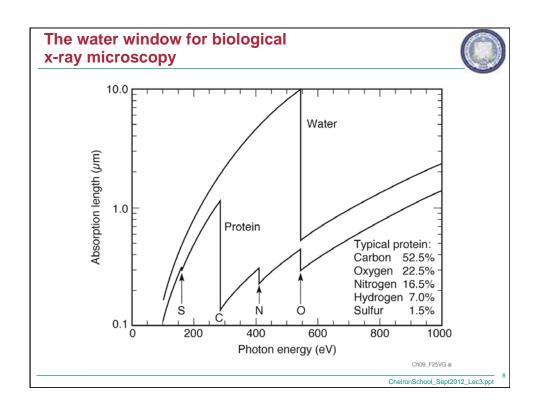


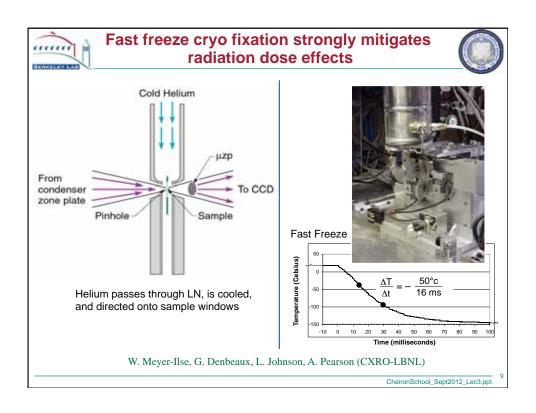
## Professor David Attwood, UC Berkeley Soft and Hard X-Ray Microscopy

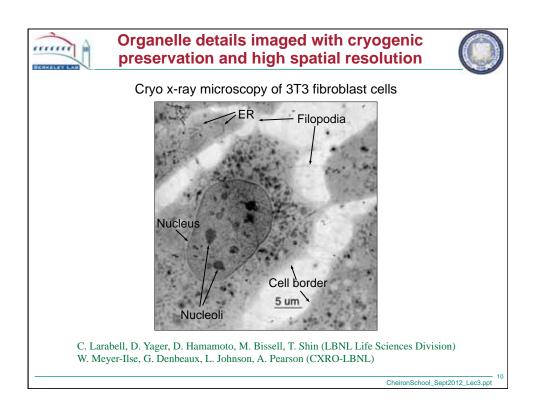


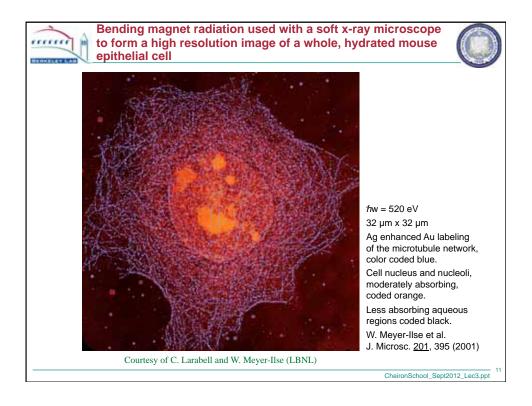


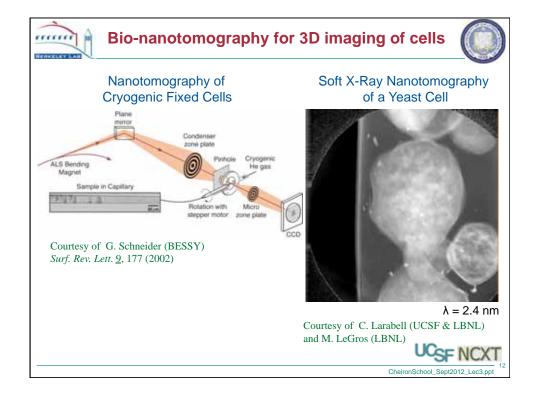


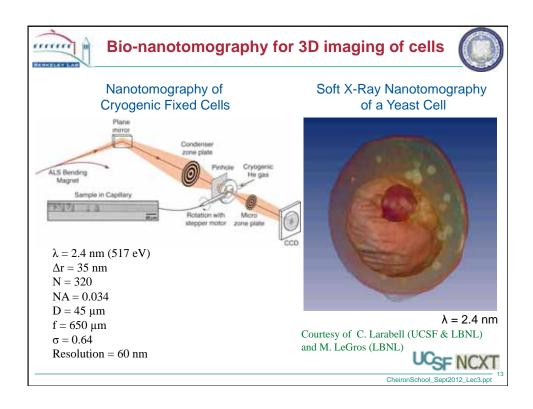


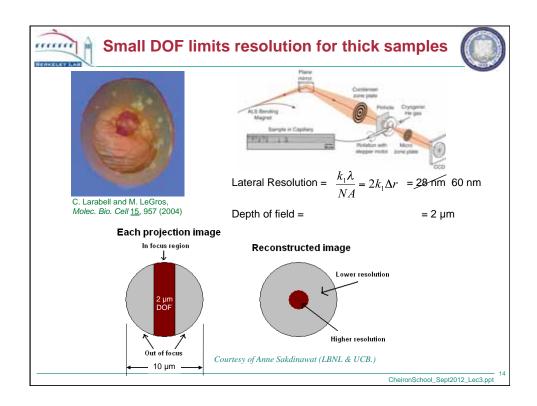


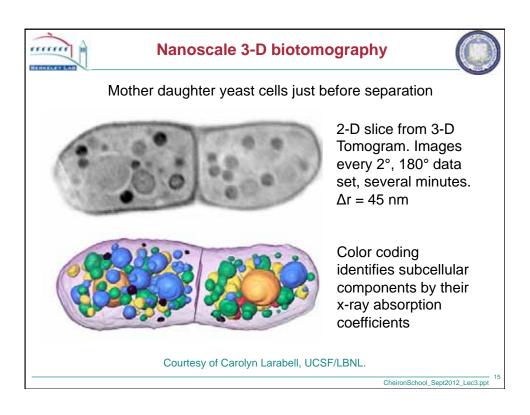


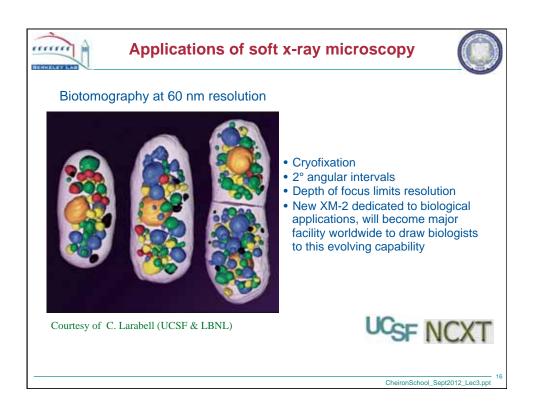


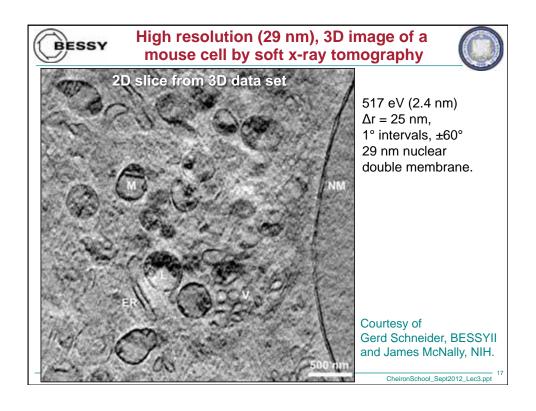


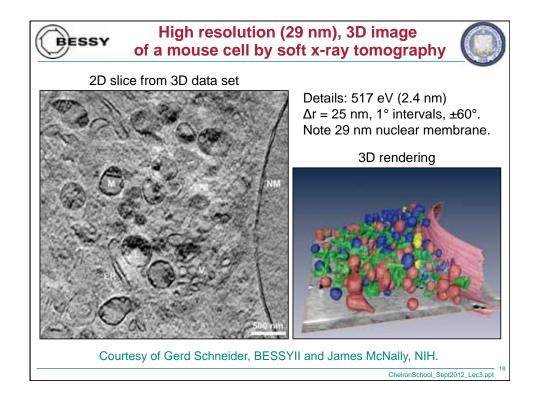


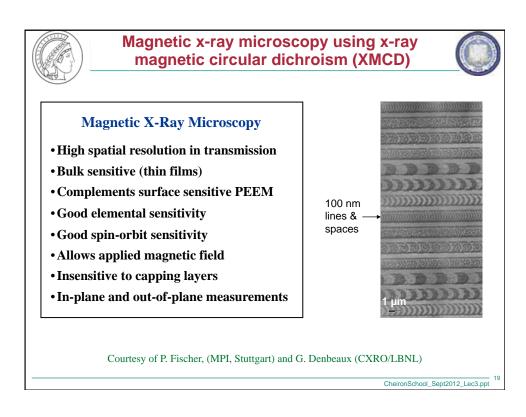


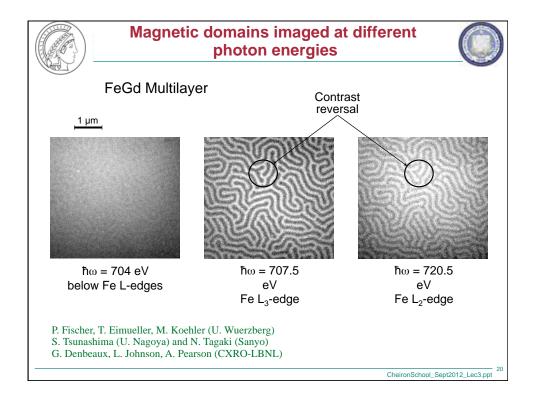


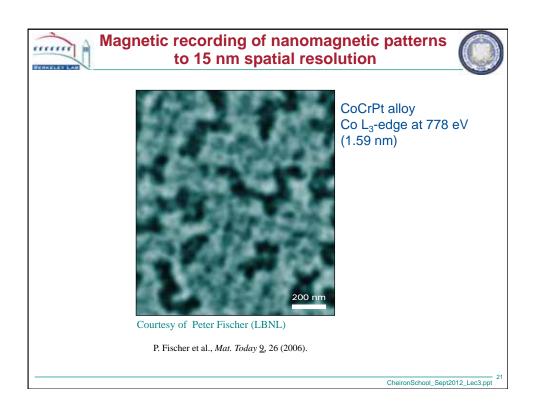


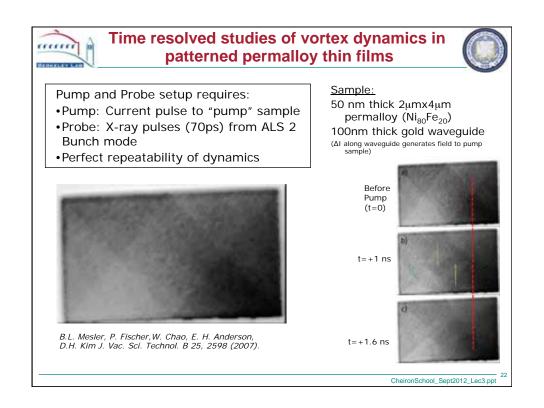


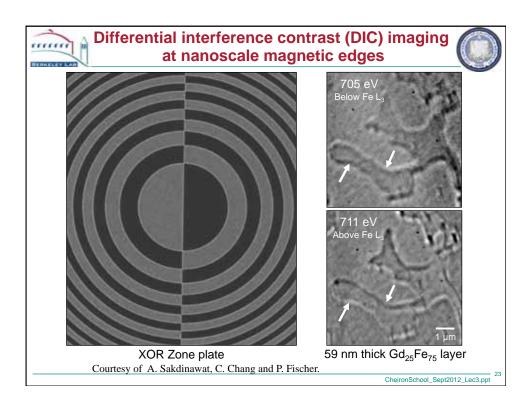


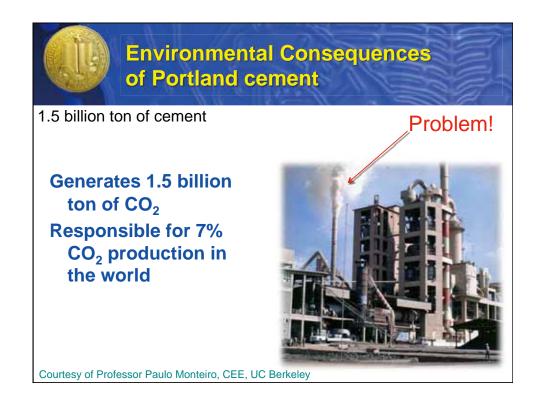


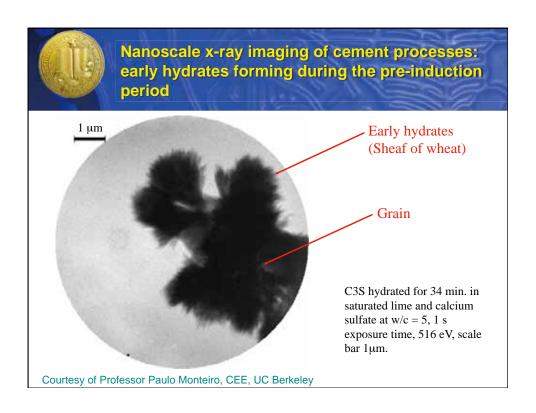


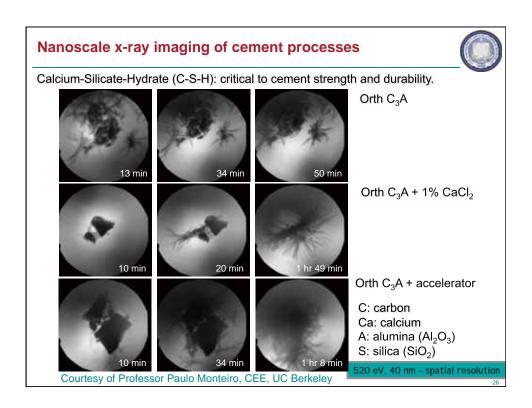


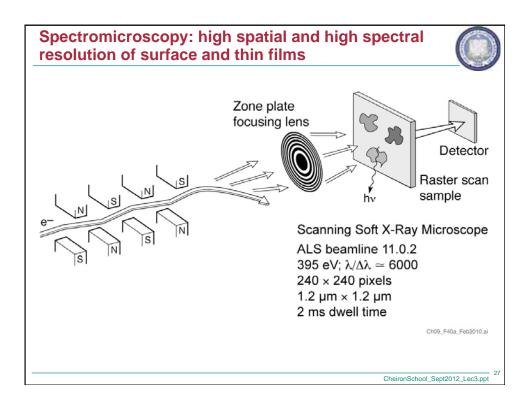


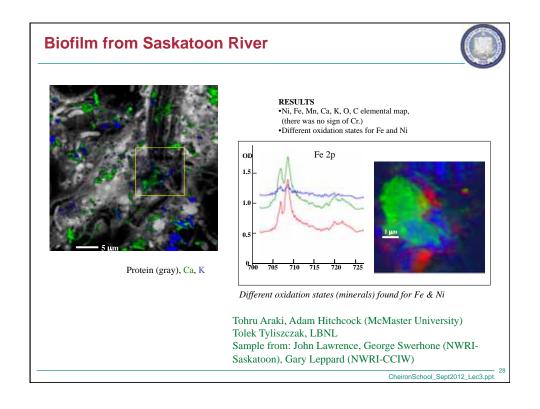


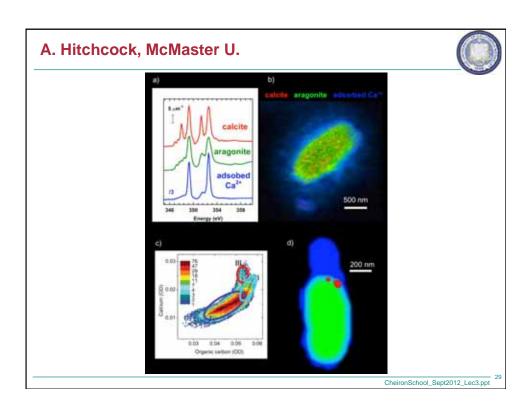


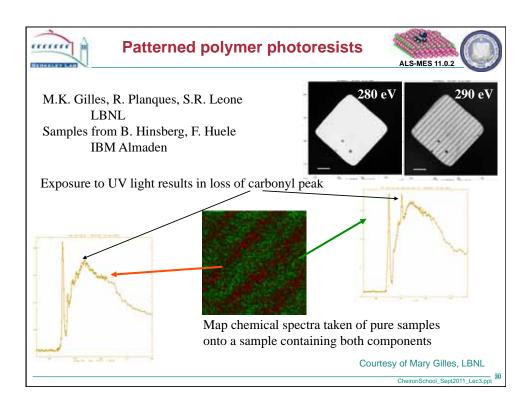












## Hard x-ray zone plate microscopy



- Shorter wavelengths, potentially better spatial resolution and greater depth-of-field.
- Less absorption (β); phase shift (δ) dominates, higher efficiency.
- Thicker structures required (e.g., zones), higher aspect ratios pose nanofabrication challenges.
- Contrast of nanoscale samples minimal; will require good statistics, uniform background, dose mitigation.

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